Se	Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/632,554	TAKANO ET AL.	
Examiner	Art Unit	
Shih-wen Hsieh	2861	

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	updated	8/16/2005	swH
400	updated	8/16/2005	SWH

ERFERENC	CE SEARCH	ED
Subclass	Date	Examiner
37,8	8/16/2005	swH
59	8/16/2005	SWH
	Subclass 37,8	37,8 8/16/2005

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